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United States Patent [19]

Fukumoto et al.

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[54] HARDNESS TESTING APPARATUS

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[**] Term: 14 Years

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[52] U.S. Cl. D10/75

[58] Field of Search D10/46, 75; 73/78, 79, 73/80, 81, 82, 83, 84; 356/378

[56] References Cited

U.S. PATENT DOCUMENTS

D. 283,599	4/1986	Biddle, Jr. et al.	D10/46
3,102,417	9/1963	Chambers	73/81
3,757,567	9/1973	Worden	73/81
4,118,975	10/1978	Iwasaki	73/81

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[57] CLAIM

The ornamental design of a hardness testing apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a frontal elevational view showing the new design of the present invention;

FIG. 2 is a top plan view showing the new design of the present invention;

FIG. 3 is a rear elevational view showing the new design of the present invention;

FIG. 4 is a bottom view showing the new design of the present invention;

FIG. 5 is a side view showing the new design of the present invention from the right side relative to the view of FIG. 1; and,

FIG. 6 is a side view showing the new design of the present invention from the left side relative to the view of FIG. 1.

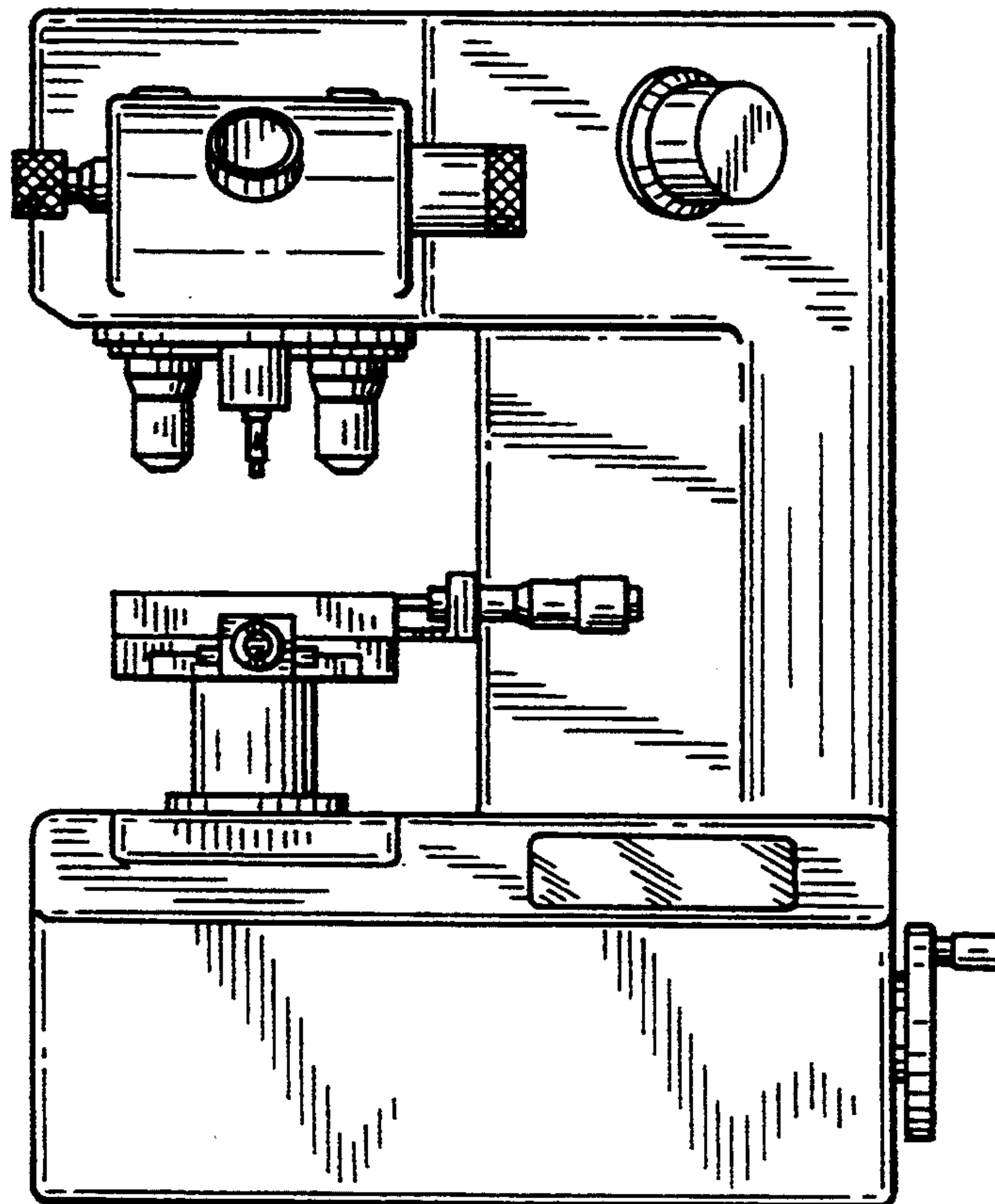


FIG. 1

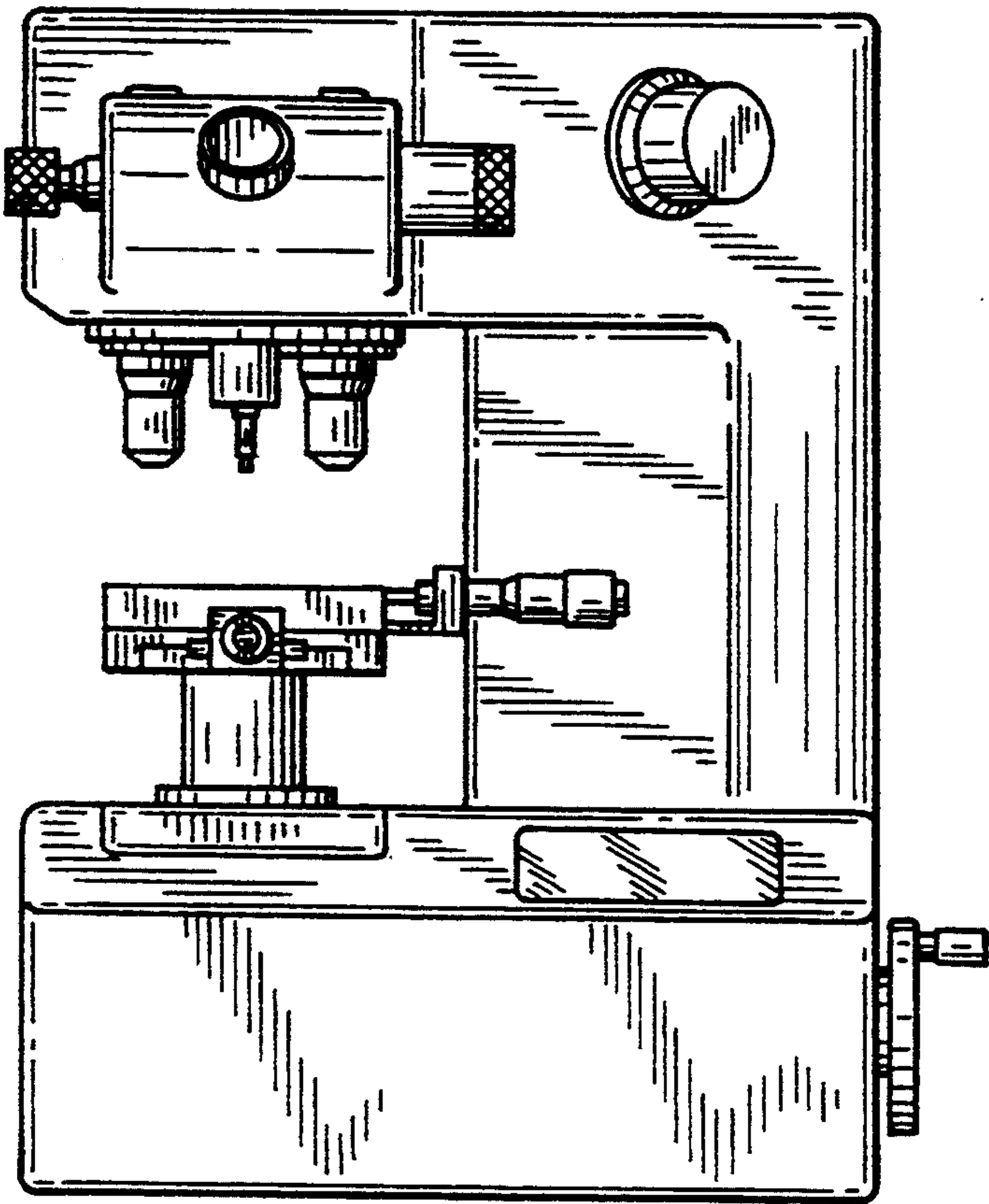


FIG. 2

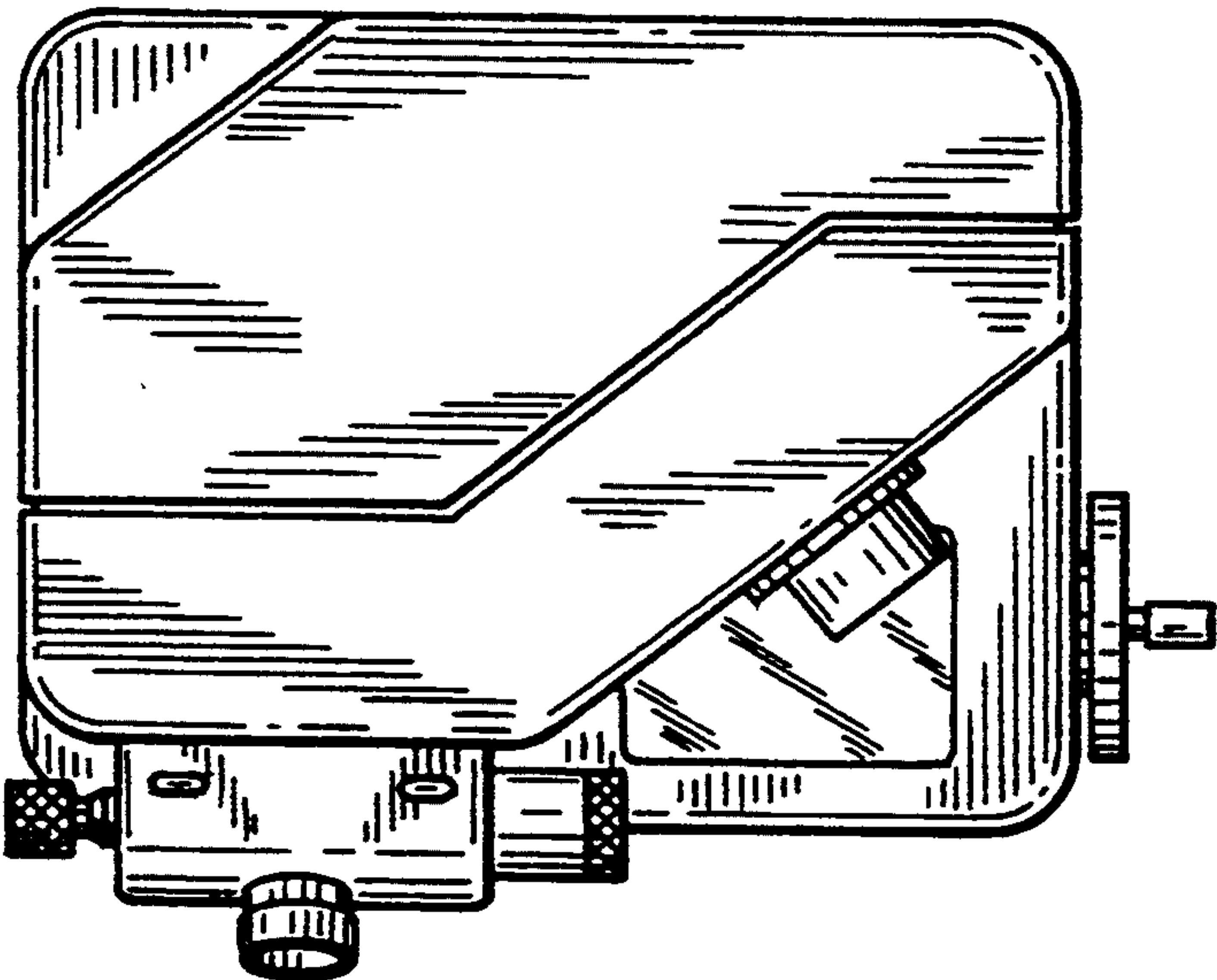


FIG. 3

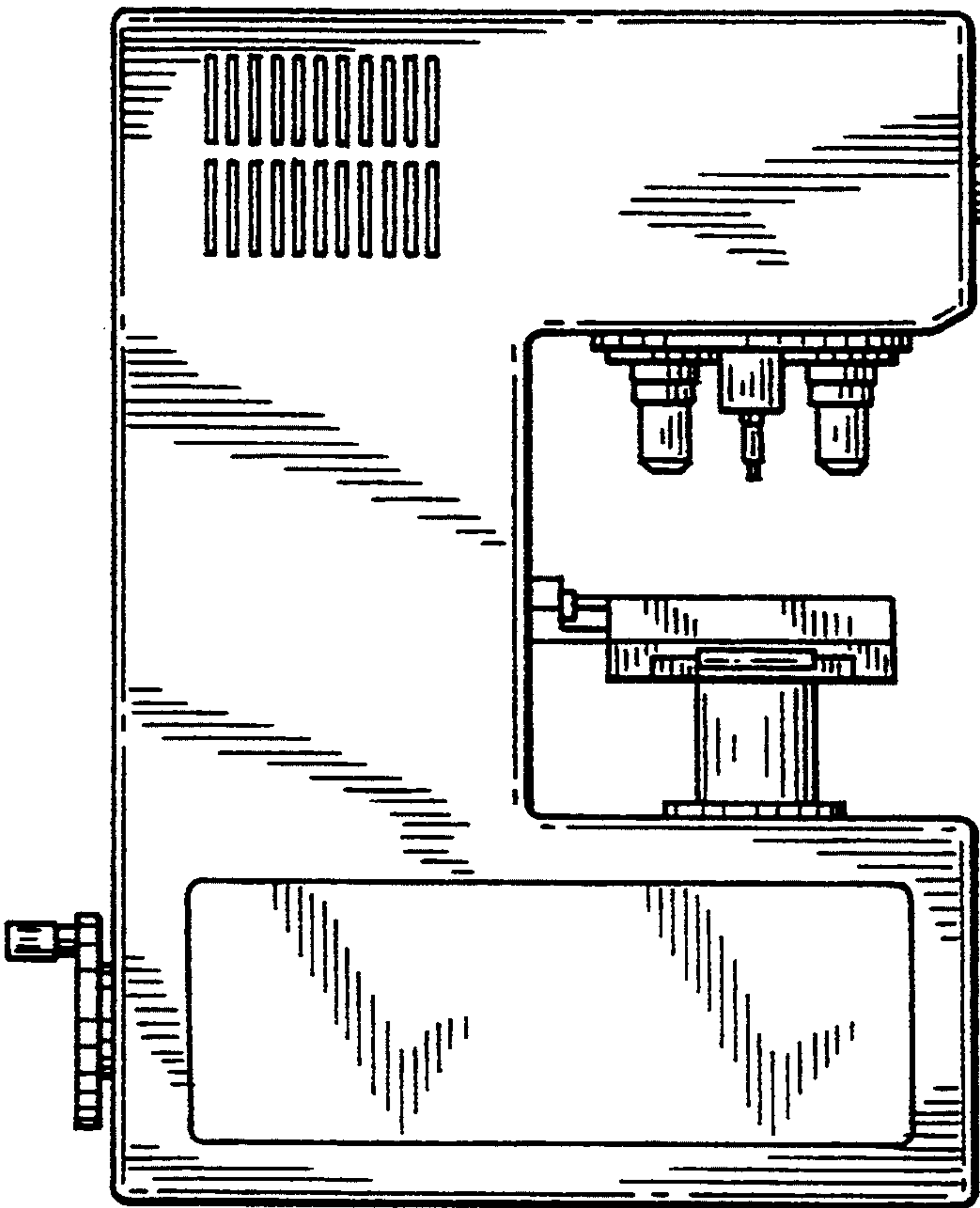


FIG. 4

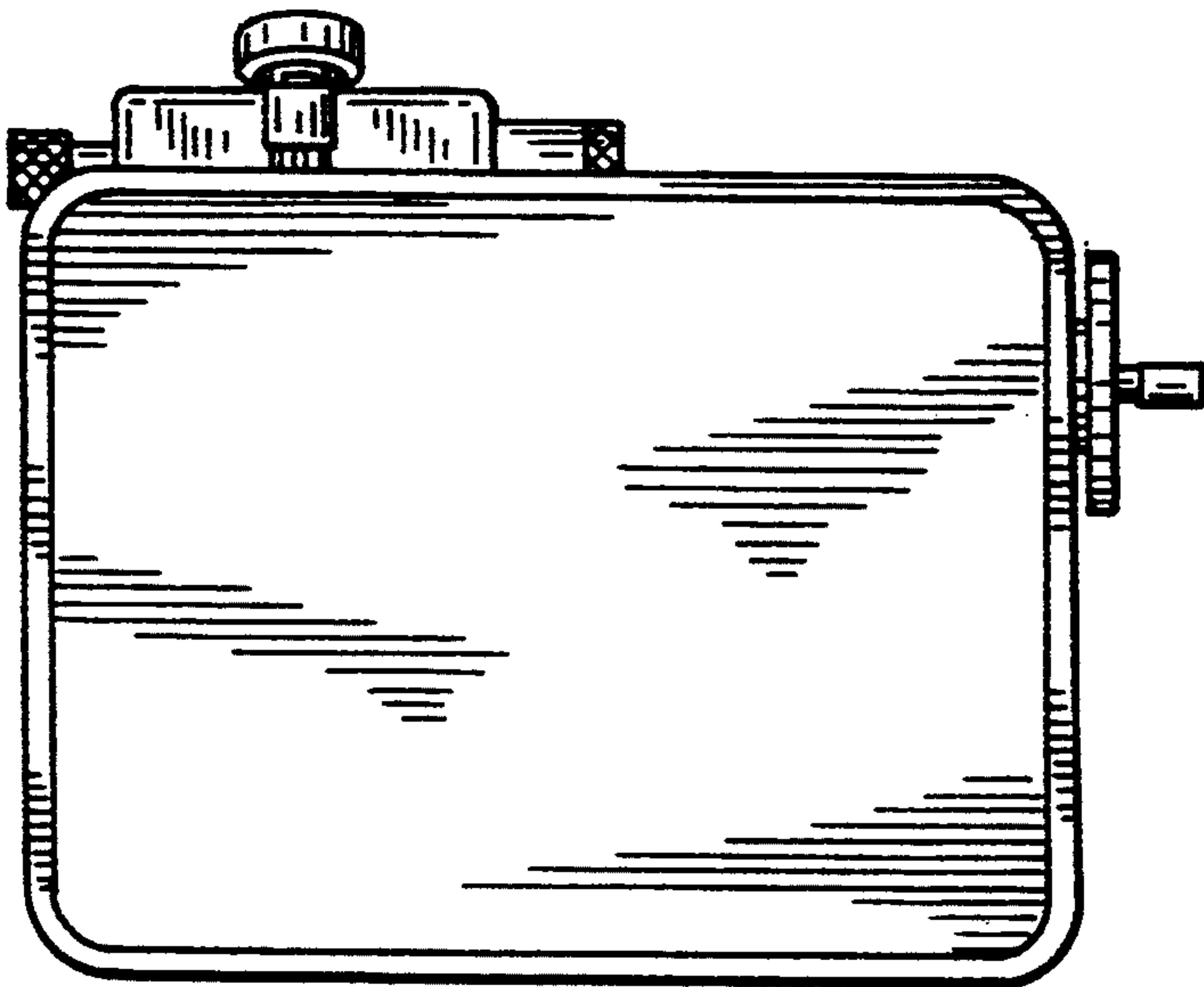


FIG. 5

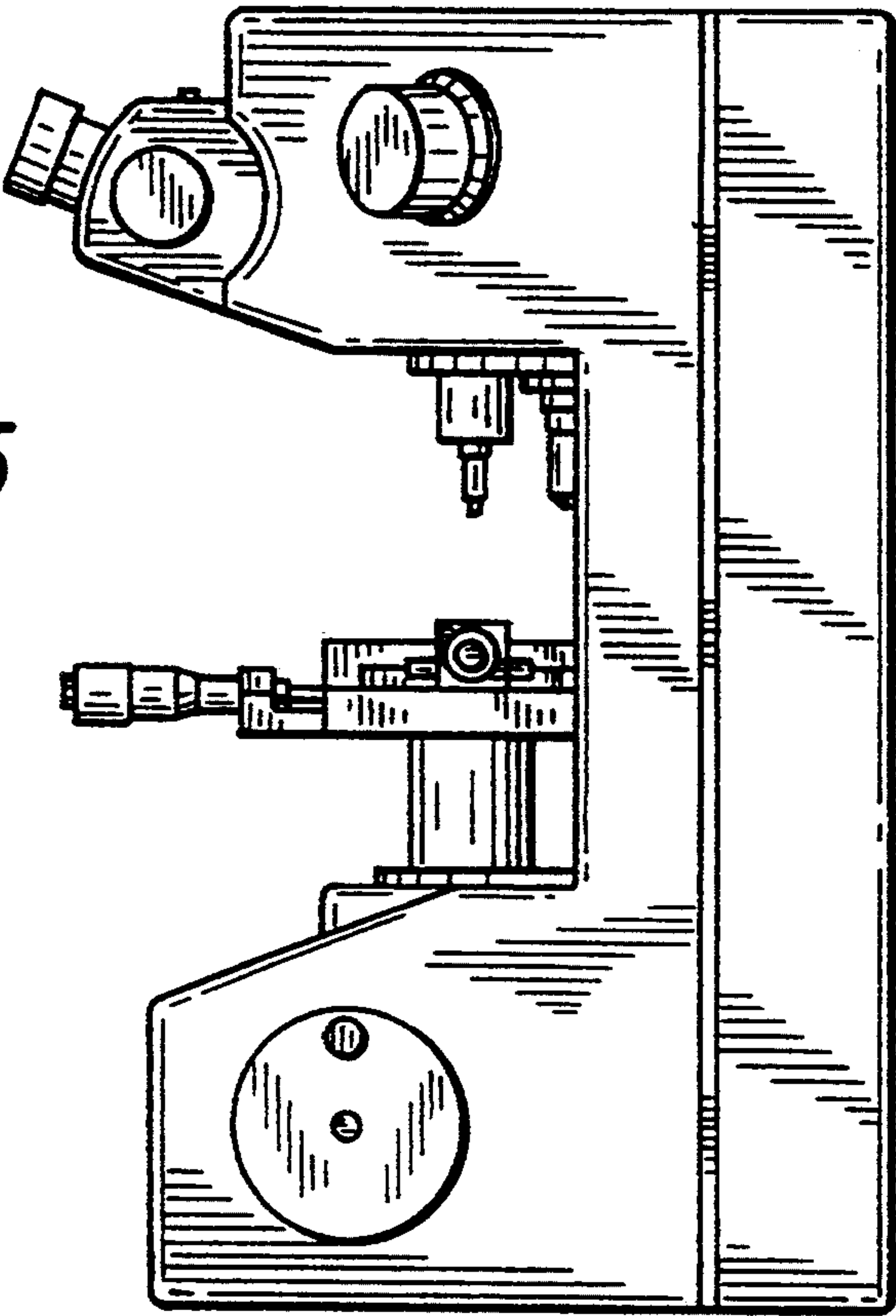


FIG. 6

